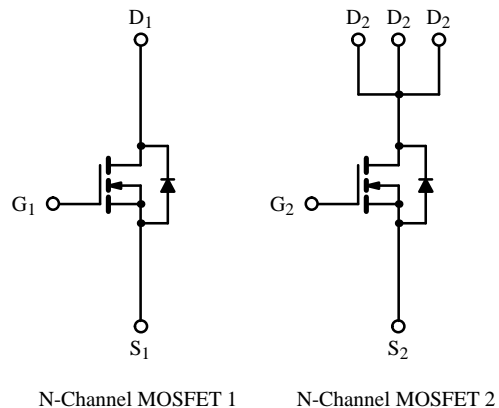
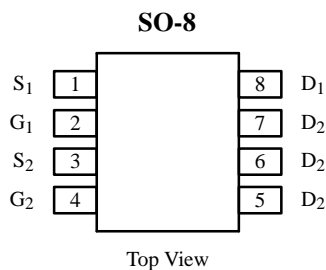


Asymmetrical Dual N-Channel Enhancement-Mode MOSFET

Product Summary

	V _{DS} (V)	r _{DS(on)} (Ω)	I _D (A)
N-Channel 1	20	0.07 @ V _{GS} = 4.5 V	± 3.0
		0.09 @ V _{GS} = 2.5 V	± 2.1
N-Channel 2		0.03 @ V _{GS} = 4.5 V	± 6.9
		0.035 @ V _{GS} = 2.5 V	± 4.9



Absolute Maximum Ratings (T_A = 25° C Unless Otherwise Noted)

Parameter	Symbol	N-Channel 1	N-Channel 2	Unit
Drain-Source Voltage	V _{DS}	20	20	V
Gate-Source Voltage	V _{GS}	± 8	± 8	
Continuous Drain Current (T _J = 150°C) ^a	I _D	T _A = 25°C	± 3.0	A
		T _A = 70°C	± 2.4	
Pulsed Drain Current	I _{DM}	± 20	± 30	A
Continuous Source Current (Diode Conduction) ^a	I _S	1.0	1.25	
Maximum Power Dissipation ^a	P _D	T _A = 25°C	1.0	W
		T _A = 70°C	0.6	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150	-55 to 150	°C

Thermal Resistance Ratings

Parameter	Symbol	N-Channel 1	N-Channel 2	Unit
Maximum Junction-to-Ambient ^a	R _{thJA}	125	55	°C/W

Notes

a. Surface Mounted on FR4 Board, t ≤ 10 sec.

Updates to this data sheet may be obtained via facsimile by calling Siliconix FaxBack, 1-408-970-5600. Please request FaxBack document #70159. A SPICE Model data sheet is available for this product (FaxBack document #70565).

Specifications (T_J = 25°C Unless Otherwise Noted)

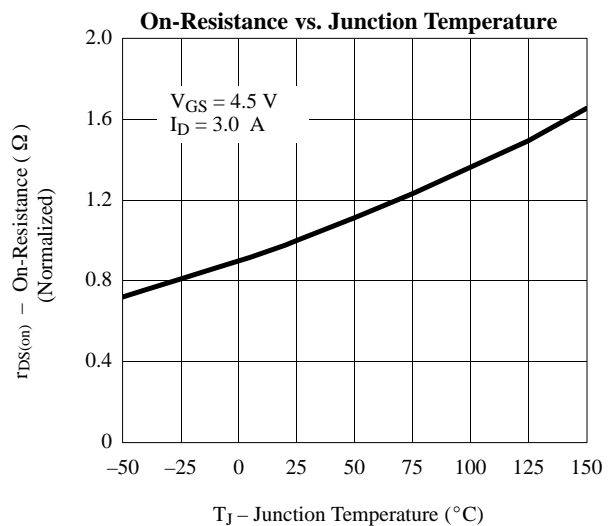
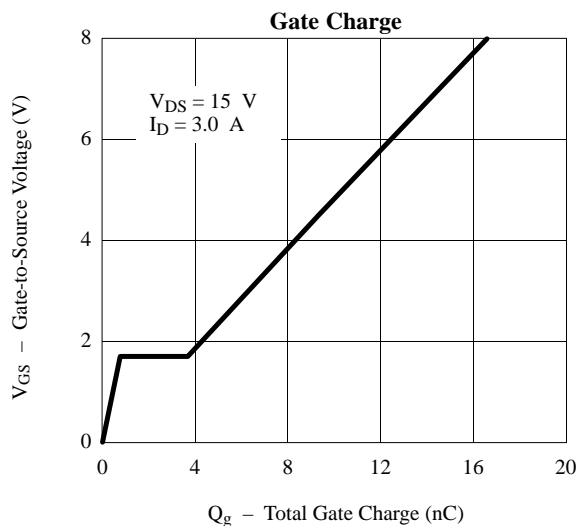
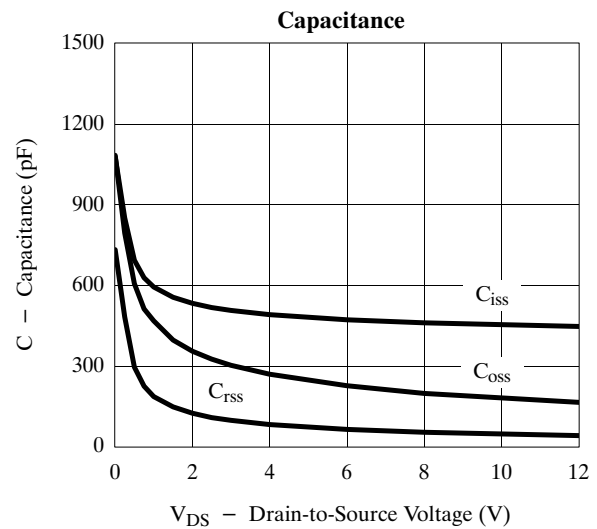
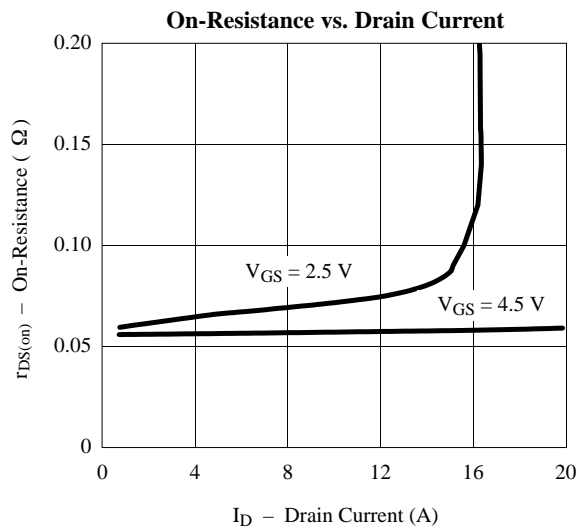
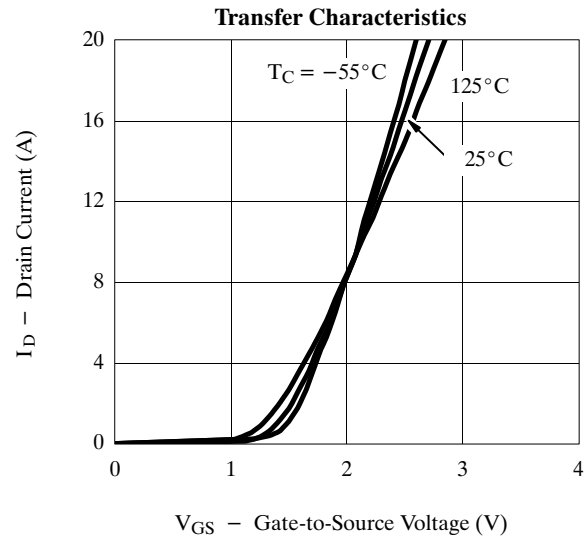
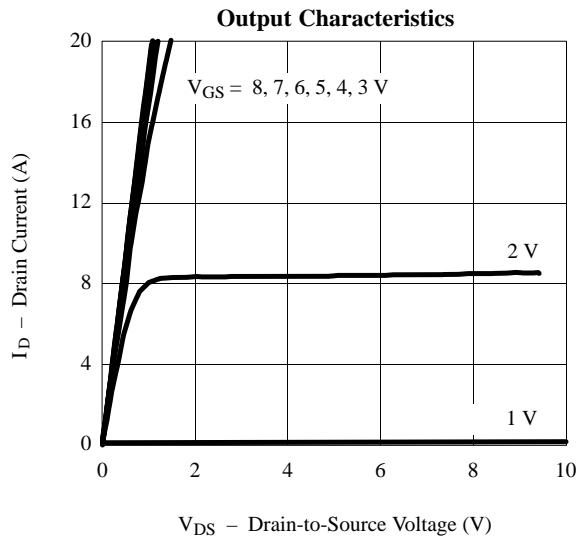
Parameter	Symbol	Test Condition	Min	Typ ^a	Max	Unit		
Static								
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	N-Ch 1	0.6		V		
			N-Ch 2	0.6				
Gate-Body Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 8 V	N-Ch 1		± 100	nA		
			N-Ch 2		± 100			
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 20 V, V _{GS} = 0 V	N-Ch 1		1	μA		
			N-Ch 2		1			
		V _{DS} = 20 V, V _{GS} = 0 V, T _J = 70°C	N-Ch 1		5			
			N-Ch 2		5			
On-State Drain Current ^b	I _{D(on)}	V _{DS} = 5 V, V _{GS} = 4.5 V	N-Ch 1	10		A		
			N-Ch 2	10				
Drain-Source On-State Resistance ^b	r _{DS(on)}	V _{GS} = 4.5 V, I _D = 3.0 A	N-Ch 1		0.050	0.07	Ω	
		V _{GS} = 4.5 V, I _D = 6.9 A	N-Ch 2		0.020	0.03		
		V _{GS} = 2.5 V, I _D = 2.1 A	N-Ch 1		0.060	0.09		
		V _{GS} = 2.5 V, I _D = 4.9 A	N-Ch 2		0.025	0.035		
Forward Transconductance ^b	g _{fs}	V _{DS} = 15 V, I _D = 3.0 A	N-Ch 1		12	S		
		V _{DS} = 15 V, I _D = 6.9 A	N-Ch 2		34			
Diode Forward Voltage ^b	V _{SD}	I _S = 1.0 A, V _{GS} = 0 V	N-Ch 1		0.8	1.2	V	
		I _S = 1.25 A, V _{GS} = 0 V	N-Ch 2		0.7	1.2		
Dynamic^a								
Total Gate Charge	Q _g	N-Channel 1 V _{DS} = 10 V, V _{GS} = 4.5 V, I _D = 3.0 A N-Channel 2 V _{DS} = 10 V, V _{GS} = 4.5 V, I _D = 6.9 A	N-Ch 1		16	40	nC	
			N-Ch 2		18	40		
Gate-Source Charge	Q _{gs}		N-Ch 1		3			
			N-Ch 2		2.5			
Gate-Drain Charge	Q _{gd}		N-Ch 1		6			
			N-Ch 2		4			
Turn-On Delay Time	t _{d(on)}	N-Channel 1 V _{DD} = 10 V, R _L = 10 Ω I _D ≅ 1 A, V _{GEN} = 4.5 V, R _G = 6 Ω N-Channel 2 V _{DD} = 10 V, R _L = 10 Ω I _D ≅ 1 A, V _{GEN} = 4.5 V, R _G = 6 Ω	N-Ch 1		37	60	ns	
			N-Ch 2		35	60		
Rise Time	t _r		N-Ch 1		66	100		
			N-Ch 2		65	100		
Turn-Off Delay Time	t _{d(off)}		N-Ch 1		56	100		
			N-Ch 2		100	150		
Fall Time	t _f		N-Ch 1		57	100		
			N-Ch 2		33	60		
Source-Drain Reverse Recovery Time	t _{rr}		I _F = 1.0 A, di/dt = 100 A/μs	N-Ch 1		26		70
			I _F = 1.25 A, di/dt = 100 A/μs	N-Ch 2		50		100

Notes

- a. For design aid only; not subject to production testing.
 b. Pulse test; pulse width ≤ 300 μs, duty cycle ≤ 2%.

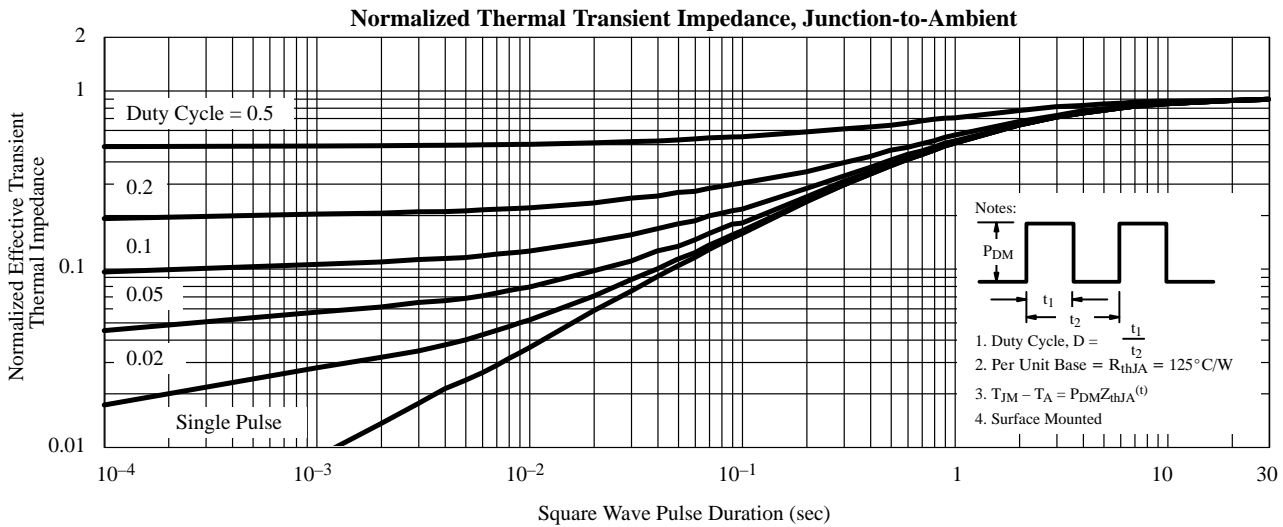
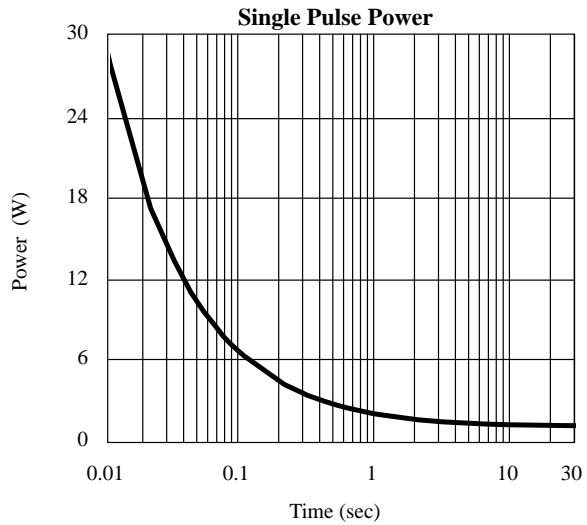
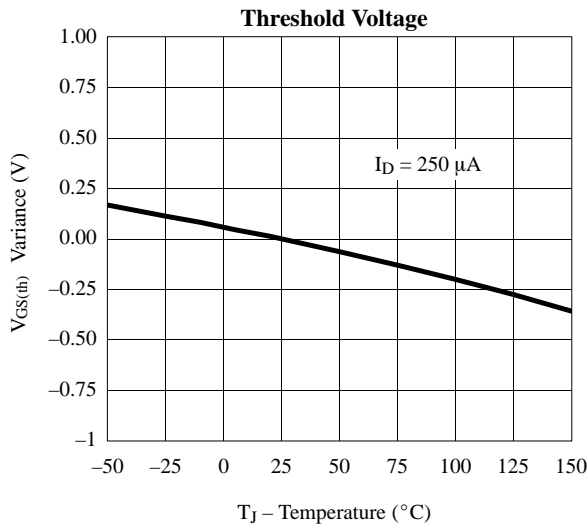
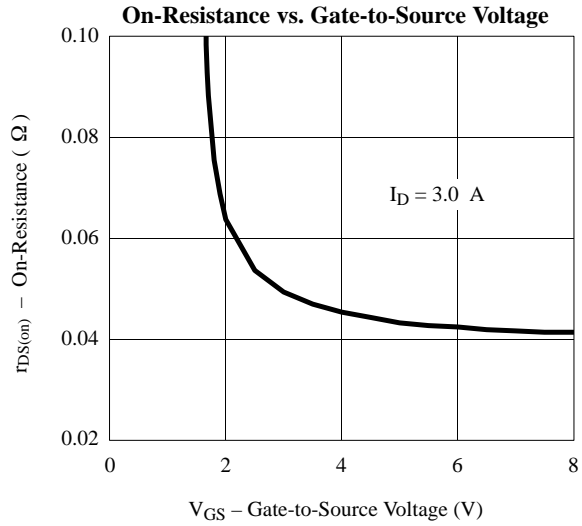
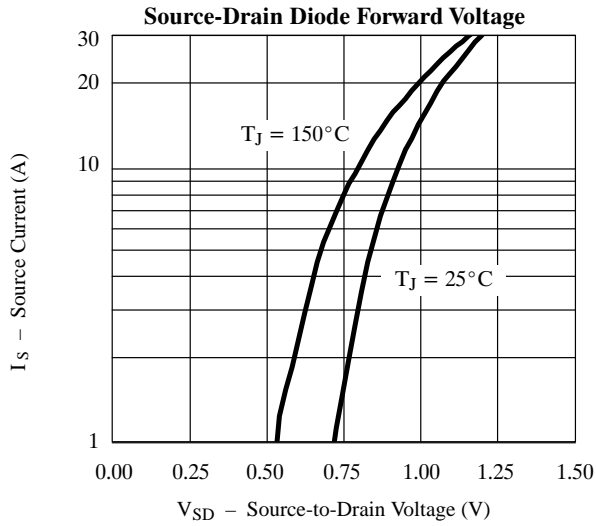
Typical Characteristics (25°C Unless Noted)

N-Channel 1



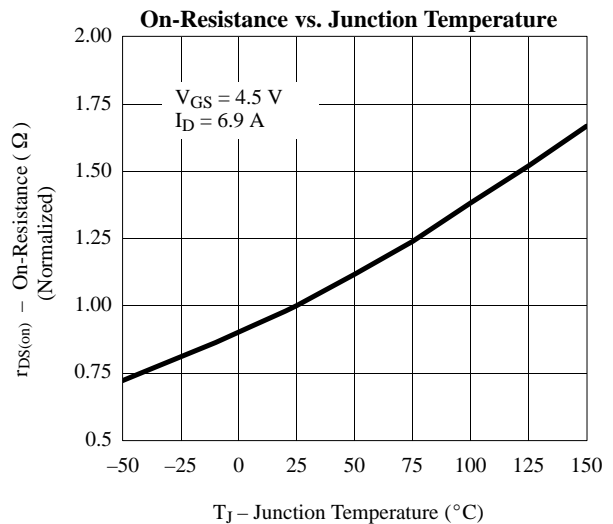
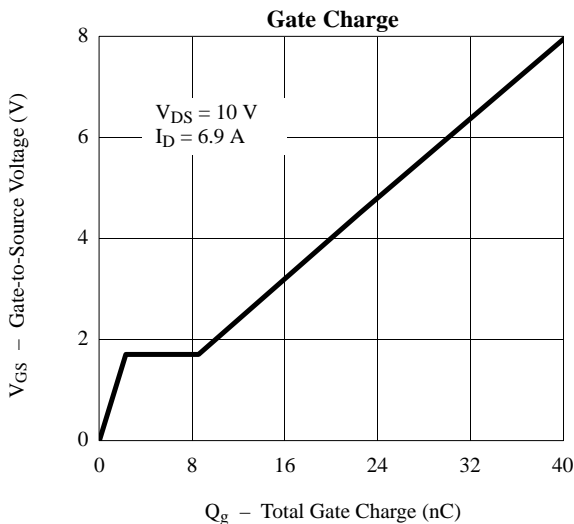
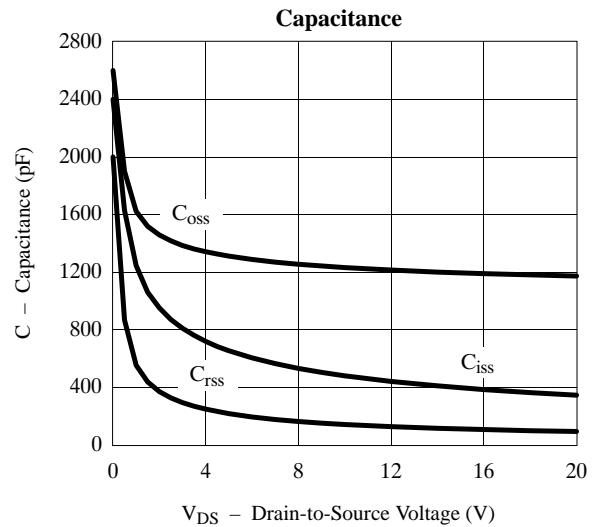
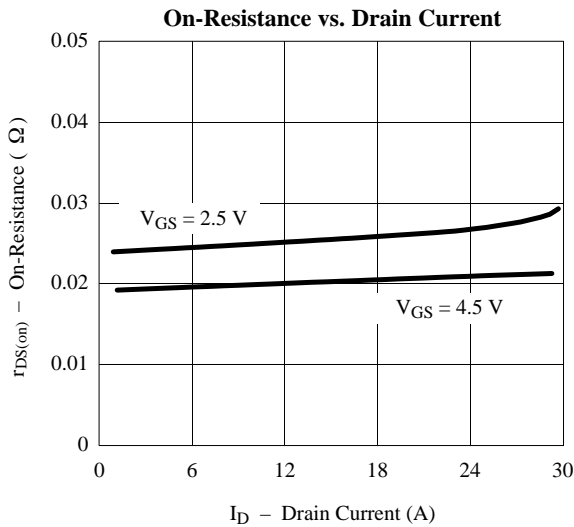
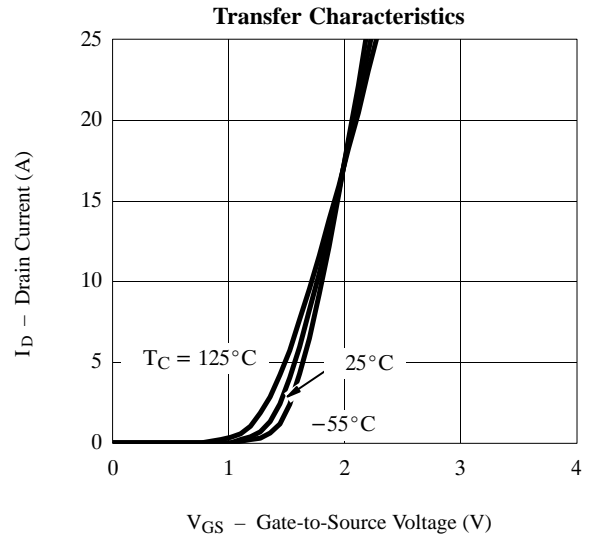
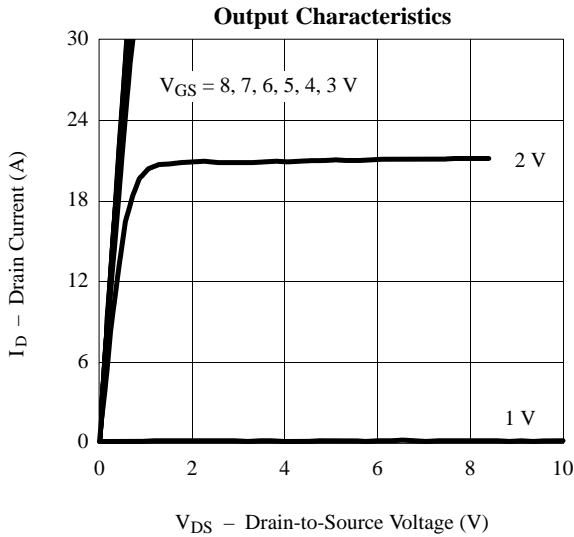
Typical Characteristics (25°C Unless Noted)

N-Channel 1



Typical Characteristics (25°C Unless Noted)

N-Channel 2



Typical Characteristics (25°C Unless Noted)

N-Channel 2

